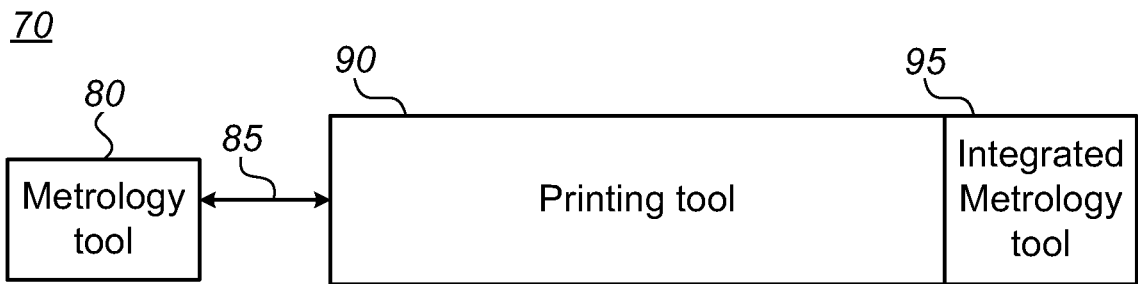
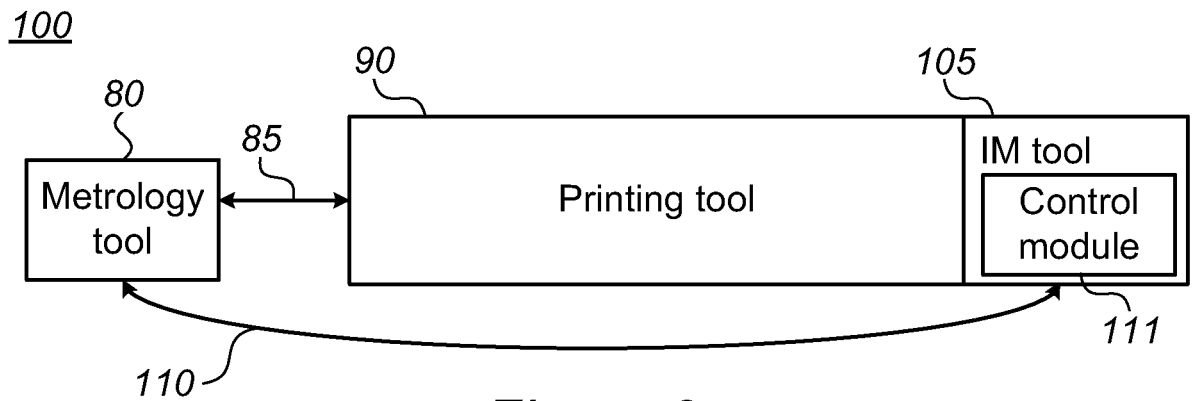
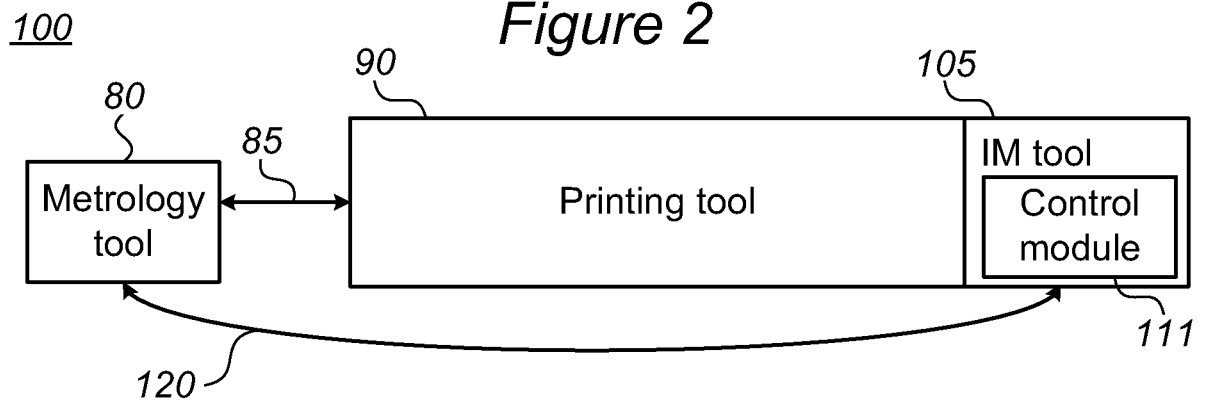
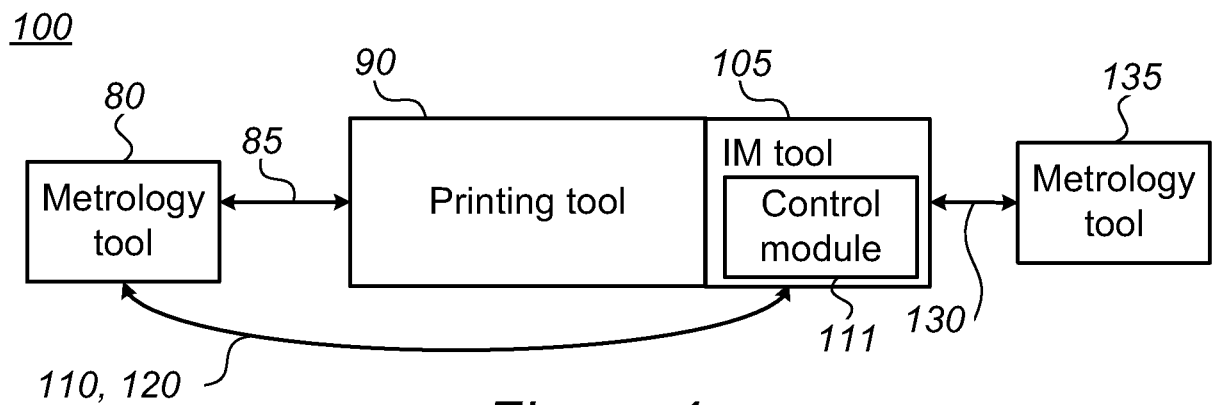
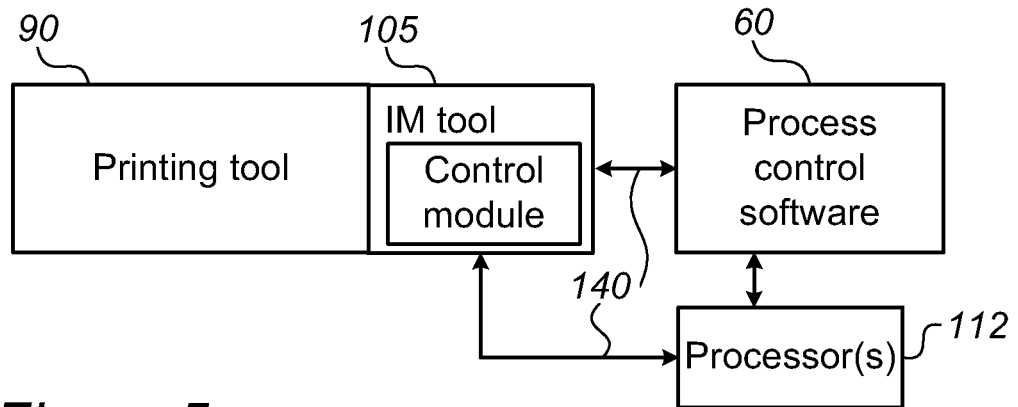
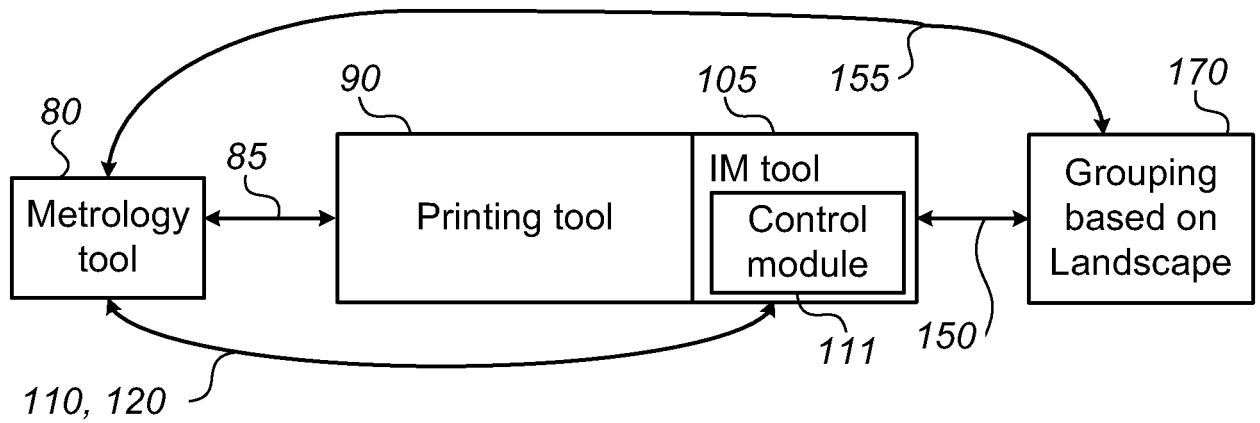
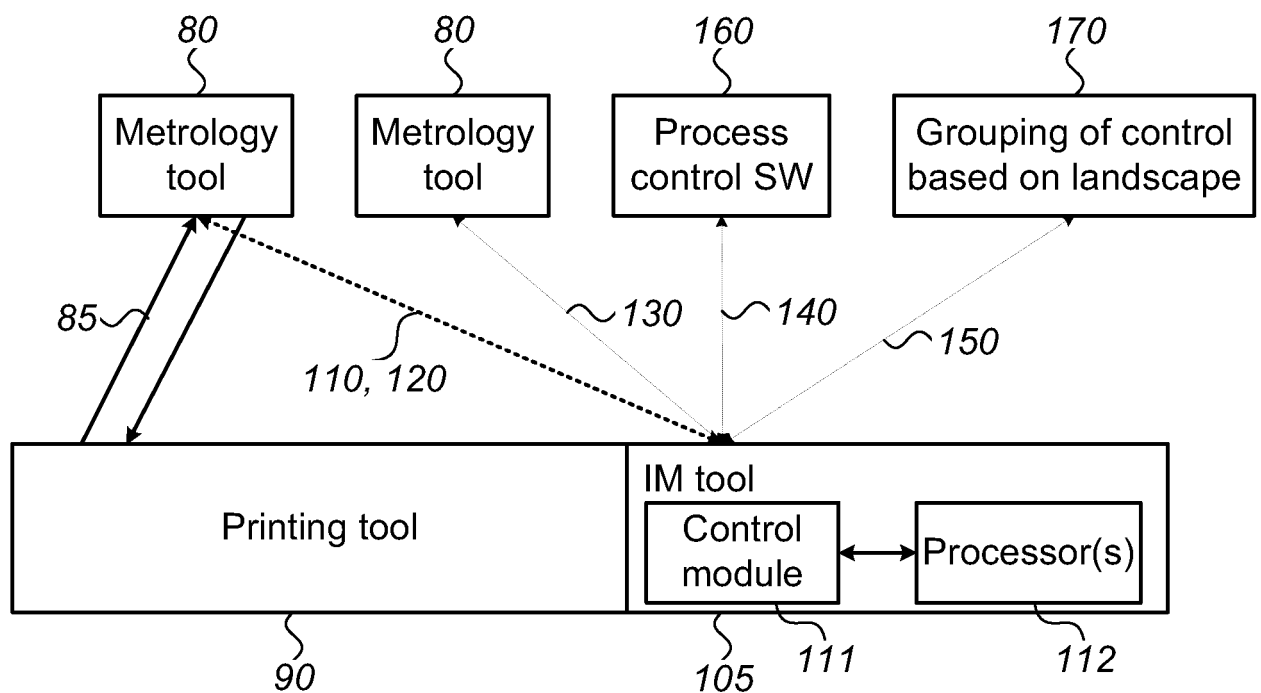


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*Figure 1 – Prior art**Figure 2**Figure 3**Figure 4*

100*Figure 5*100*Figure 6*100*Figure 7*

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200

210 Monitoring, by the integrated metrology tool of a lithography printing tool, metrology measurements by the integrated and standalone metrology tools with respect to specified temporal limitations of the printing tool

220

Allocating, by the integrated metrology tool, metrology measurements thereby and by the standalone metrology tool with respect to specified temporal limitations of the printing tool

230

Adjusting and/or optimizing a metrology measurement recipe according to the specified temporal limitations

240

Optimizing process parameters of the printing tool by process control software, based on metrology measurements by at least the integrated metrology tool

250

Grouping process parameters of the printing tool according to a metrology measurements landscape

260

Deriving the metrology measurements landscape by at least the integrated metrology tool

*Figure 8*